


<b>Search Notes</b>  	<b>Application/Control No.</b>  09815760	<b>Applicant(s)/Patent Under Reexamination</b>  DEAN, ALAN DEREK
	<b>Examiner</b>  Haresh N Patel	<b>Art Unit</b>  2154

SEARCHED			
Class	Subclass	Date	Examiner
709	200-203, 217-228	7/28/2008	H.P.

SEARCH NOTES		
Search Notes	Date	Examiner
EAST; US-PAT, US-PUB, EPO, JPO, USOCR, DERWENT, IBM_TDB; IEEE XPLORE, ACM DIGITAL LIBRARY, GOOGLE.	7/28/2008	H.P.

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner
709	206, 217, 224	7/28/2008	H.P.